

IDS 11/30/07

Based on Form PTO-1449 (350) <div style="border: 1px solid black; border-radius: 50%; padding: 10px; display: inline-block; text-align: center;"> NOV 30 2007 <small>U.S. PATENT & TRADEMARK OFFICE</small> </div>	ATTY. DOCKET NO. 455610-2590.1	SERIAL NO. 10/673,736
LIST OF REFERENCES CITED BY APPLICANT (Use several sheets if necessary)		
APPLICANT Martin Thomas Miller		
FILING DATE September 29, 2003		GROUP 2117

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
	AL							
	AM							
	AN							
	AO							
	AP							

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)

AQ		Technology Standards, Tektronix Website (www.tek.com/M Measurement/Solutions/tech_standards/index.html?wt=257), July 16, 2003
AR		Communications Signal Analyzer, Communications Eye-diagram Measurements Software, Tektronix website (http://www.tektronix.com), May 12, 2003
AS		RT-Eye™ Serial Data Compliance and Analysis Software, Tektronix website(www.tektronix.com/accessories), September 20, 2002
AT		Design of FIR Filters by Windowing, HST-5821/6.555/16.456J, Biomedical Signal and Image Processing Spring 2001, (http://web.mit.edu/6.555/www/fir.html), August 5, 2003
AU		A New Digital PLL at the Technische Universitaet Berlin, The Cooperation Project, (http://www.tdl.com/~gotsch/ruberlin.htm), August 5, 2003.
AV		Low Jitter Digital PLL - ZL 30407, Zarlink Semiconductor, (http://products.zarlink.com/product_portlets/new_timer.htm) , August 5, 2003
		Williams, Michael, "A Discussion of Methods for Measuring Low-Amplitude Jitter", International Test Conference, Paper 28.1, pp. 646-652, 1995 IEEE
		University of New Hampshire, "Fast Ethernet, Clause 25 Physical Medium Dependent Test Suite Version 2.5, February 13, 2003

EXAMINER /Phung Chung/	DATE CONSIDERED 02/17/2008
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* EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.



IDS 11/5/07
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Based on Form PTO-1449 (3/90)	ATTY. DOCKET NO. 455610-2590.1	SERIAL NO. 10/673,736
	APPLICANT Martin MILLER et al.	
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U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	AA	3 449 671	06/1969	Long Gordon D.			
	AB	3 778 550	12/1973	David et al.			
	AC	4 375 694	03/1983	Kuhn, William B.			
	AD	4 964 117	10/1990	Shier, John S.			
	AE	6 738 992	05/2004	Warwar et al.			
	AF	2004 0123208	06/2004	Miller et al.			
	AG	2004 0153883	08/2004	Miller et al.			
	AH	3, 562 710	2/9/1971	Halleck, Michael E.			
	AI	4, 100, 531	7/11/1978	Fletcher, James C.			
	AJ	5, 761, 216 A	6/2/1998	Tetsuo, Sotome			
	AK	5,159,609	10/27/1992	Palicot			
	AL	5,222,101	6/22/1993	Ariyavisitakul			
	AM	5,907,587	5/25/1999	Sokoler			
	AN	6,212,246	3/4/2001	Hendrickson			
	AO	6,675,328	1/6/2004	Krishnamachari			
	AP	6 850 852	02/2005	Ferguson et al.			
	AQ	6 836 738	12/2004	Sepp et al.			
	AR	2002 0128787 A1	09/2002	Seng et al.			

FOREIGN PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO
	AS						
	AT						

OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.)

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U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	AV	2002 0034337 A1	03/2002	Shekter, Jonathan Martin			
	AW	2002 0018572 A1	02/2002	Rhoads, Geoffrey B.			
	AX	6 853 696	02/2005	Moser et al.			
	AY	2001 0021151	09/2001	Verboom, Johannes et al.			
	AZ	6 463 109 B1	10/2002	McCormack et al.			
	BA	6 996 202 B2	02/2006	McCormack et al.			
	BB	2004 0123018 A1	06/2004	Miller et al.			
	BC	2004 0123191 A1	06/2004	Salant et al.			
	BD	6 922 384 B2	07/2005	Miyashita et al.			
	BE	3 449 671	06/1969	Long Gordon D.			
	BF	3 778 550	12/1973	David et al.			
	BG	4 375 694	03/1983	Kuhn, William B.			
	BH	4 964 117	10/1990	Shier, John S.			
	BI	6 738 992	05/2004	Warwar et al.			
	BJ	2004 0123208	06/2004	Miller et al.			
	BK	2004 0153883	08/2004	Miller et al.			

FOREIGN PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO
	BL	DE 2462046 A1	11/1975	Germany			
	BM	WO 2004 032049 A2	04/2004	PCT			
	BN	GB 2 138 575 A	10/24/1984	United Kingdom			

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